



Standard Test Method for Analysis of Carbon and Low-Alloy Steel by Spark Atomic Emission Spectrometry¹

This standard is issued under the fixed designation E415; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This test method covers the simultaneous determination of 20 alloying and residual elements in carbon and low-alloy steels by spark atomic emission vacuum spectrometry in the mass fraction ranges shown (Note 1).

Element	Composition Range, %	
	Applicable Range, Mass Fraction % ^A	Quantitative Range, Mass Fraction % ^B
Aluminum	0 to 0.075	0.02 to 0.075
Arsenic	0 to 0.1	0.05 to 0.1
Boron	0 to 0.007	0.002 to 0.007
Calcium	0 to 0.003	0.001 to 0.003
Carbon	0 to 1.1	0.08 to 1.1
Chromium	0 to 2.25	0.02 to 2.25
Cobalt	0 to 0.18	0.008 to 0.18
Copper	0 to 0.5	0.04 to 0.5
Manganese	0 to 2.0	0.10 to 2.0
Molybdenum	0 to 0.6	0.03 to 0.6
Nickel	0 to 5.0	0.02 to 5.0
Niobium	0 to 0.085	0.02 to 0.085
Nitrogen	0 to 0.015	0.004 to 0.015
Phosphorous	0 to 0.085	0.02 to 0.085
Silicon	0 to 1.15	0.07 to 1.15
Sulfur	0 to 0.055	0.01 to 0.055
Tin	0 to 0.045	0.01 to 0.045
Titanium	0 to 0.2	0.004 to 0.2
Vanadium	0 to 0.3	0.004 to 0.3
Zirconium	0 to 0.05	0.02 to 0.05

^A Applicable range in accordance with Guide E1763 for results reported in accordance with Practice E1950.

^B Quantitative range in accordance with Practice E1601.

NOTE 1—The mass fraction ranges of the elements listed have been established through cooperative testing² of reference materials. Included, in addition to the original data of Test Method E415 – 71, are data from cooperative testing of a broader range of reference materials to expand the element mass fraction ranges.

1.2 This test method covers analysis of specimens having a diameter adequate to overlap and seal the bore of the spark

stand opening. The specimen thickness can vary significantly according to the design of the spectrometer stand, but a thickness between 10 mm and 38 mm has been found to be most practical.

1.3 This test method covers the routine control analysis in iron and steelmaking operations and the analysis of processed material. It is designed for chill-cast, rolled, and forged specimens. Better performance is expected when reference materials and specimens are of similar metallurgical condition and composition. However, it is not required for all applications of this standard.

1.4 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 ASTM Standards:³

- E135 Terminology Relating to Analytical Chemistry for Metals, Ores, and Related Materials
- E305 Practice for Establishing and Controlling Atomic Emission Spectrochemical Analytical Curves
- E350 Test Methods for Chemical Analysis of Carbon Steel, Low-Alloy Steel, Silicon Electrical Steel, Ingot Iron, and Wrought Iron
- E406 Practice for Using Controlled Atmospheres in Spectrochemical Analysis
- E1019 Test Methods for Determination of Carbon, Sulfur, Nitrogen, and Oxygen in Steel, Iron, Nickel, and Cobalt Alloys by Various Combustion and Fusion Techniques
- E1329 Practice for Verification and Use of Control Charts in Spectrochemical Analysis
- E1601 Practice for Conducting an Interlaboratory Study to Evaluate the Performance of an Analytical Method
- E1763 Guide for Interpretation and Use of Results from Interlaboratory Testing of Chemical Analysis Methods

¹ This test method is under the jurisdiction of ASTM Committee E01 on Analytical Chemistry for Metals, Ores, and Related Materials and is the direct responsibility of Subcommittee E01.01 on Iron, Steel, and Ferroalloys.

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² Supporting data have been filed at ASTM International Headquarters and may be obtained by requesting Research Report: RR:E2-1004.

³ For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

E1806 Practice for Sampling Steel and Iron for Determination of Chemical Composition

E1950 Practice for Reporting Results from Methods of Chemical Analysis

2.2 *Other ASTM Documents*

ASTM MNL 7 Manual on Presentation of Data and Control Chart Analysis⁴

3. Terminology

3.1 For definitions of terms used in this test method, refer to Terminology **E135**.

4. Summary of Test Method

4.1 A capacitor discharge is produced between the flat, ground surface of the disk specimen and a conically shaped electrode. The discharge is terminated at a predetermined intensity time integral of a selected iron line, or at a predetermined time, and the relative radiant energies of the analytical lines are recorded. The most sensitive lines of arsenic, boron, carbon, nitrogen, phosphorus, sulfur, and tin lie in the vacuum ultraviolet region. The absorption of the radiation by air in this region is overcome by evacuating the spectrometer and flushing the spark chamber with argon.

5. Significance and Use

5.1 This test method for the spectrometric analysis of metals and alloys is primarily intended to test such materials for compliance with compositional specifications. It is assumed that all who use this test method will be analysts capable of performing common laboratory procedures skillfully and safely. It is expected that work will be performed in a properly equipped laboratory.

6. Apparatus

6.1 *Sampling Devices:*

6.1.1 Refer to Practice **E1806** for devices and practices to sample liquid and solid iron and steel.

6.2 *Excitation Source*, capable of providing electrical parameters to spark a sample. See **11.1** for details.

6.3 *Spark Chamber*, automatically flushed with argon. The spark chamber shall be mounted directly on the spectrometer and shall be provided with a spark stand to hold a flat specimen and a lower counter electrode of rod form.

6.3.1 Follow the manufacturer's recommendations for cleaning the spark chamber (during continuous operation, this typically should be done every 24 h). Follow the manufacturer's recommendations for cleaning the entrance lens or window (verifier data or other reference sample intensity data can typically indicate when this is necessary).

6.4 *Spectrometer*, having a reciprocal linear dispersion of 0.60 nm/mm, or better, in the first order and a focal length of 0.75 m to 3 m. Its approximate range shall be from 145.0 nm to 400.0 nm. Masks shall be provided in the spectrometer to eliminate scattered radiation. The spectrometer shall be provided with an air inlet and a vacuum outlet. The spectrometer

shall be operated at a vacuum of 3.33 Pa (25 μ m of mercury) or below. The primary slit width can range from 20 μ m to 50 μ m. Secondary slit widths can vary (normally between 37 μ m and 200 μ m) depending on the element wavelength and possible interfering wavelengths.

6.5 *Measuring System*, consisting of photomultipliers (**Note 2**) having individual voltage adjustments, capacitors in which the output of each photomultiplier is stored, a voltage measuring system to register the voltages on the capacitors either directly or indirectly, and the necessary switching arrangements to provide the desired sequence of operation.

NOTE 2—Spectrometers equipped with CCD and/or CID detectors may be used provided the user can verify that the data obtained are equivalent to the precision and bias statistics in this method.

6.6 *Vacuum Pump*, capable of maintaining a vacuum of 3.33 Pa (25 μ m Hg) or less.

NOTE 3—A pump with a displacement of at least 0.23 m³/min (8 ft³/min) is usually adequate.

6.7 *Gas System*, consisting of an argon supply with pressure and flow regulation. Automatic sequencing shall be provided to actuate the flow at a given rate for a specific time interval. The flow rate may be manually or automatically controlled. The argon system shall be in accordance with Practice **E406**.

7. Reagents and Materials

7.1 *Counter Electrodes*—The counter electrodes can be silver or thoriated tungsten rods, or other material, provided it can be shown experimentally that equivalent precision and bias is obtained. The rods can vary in diameter from 1.5 mm to 6.5 mm (depending on the instrument manufacturer) and typically are machined to a 90° or 120° angled tip.

7.1.1 A black deposit will collect on the tip of the electrode. This deposit should be removed between specimens (typically with a wire brush). If not removed, it can reduce the overall intensity of the spectral radiation or transfer slight amounts of contamination between specimens, or both. The number of acceptable excitations on an electrode varies from one instrument to another, and should be established in each laboratory.

NOTE 4—It has been reported that thousands of excitations can be performed on a thoriated tungsten electrode before replacement is necessary.

7.2 *Inert Gas, Argon*, in accordance with Practice **E406**.

8. Reference Materials

8.1 *Certified Reference Materials (CRMs)*—These are available from the National Institute of Standards and Technology (NIST) and other sources and span all or part of the mass fraction ranges listed in **1.1**. They are used to calibrate the spectrometer for the elements of interest or to validate the performance of the test method. It is not recommended to use CRMs as verifiers or to establish the repeatability of the chemical measurement process. Differences can occur between CRMs and production samples prepared by the sampling procedures recommended in this test method. Certain element's (for example, sulfur) calibrations may need to be

⁴ ASTM Manual Series, ASTM International, 8th edition, 2010.

corrected with values from reference materials made by normal production sampling techniques and analyzed by Test Methods E350 and E1019.

NOTE 5—Certified Reference Materials manufactured by NIST are trademarked with the name, “Standard Reference Materials, SRMs.”

8.2 *Reference Materials (RMs)*—These are available from multiple suppliers or can be developed in house. RMs are typically used to control (verifiers) and drift correct (standards) the spectrometer. These reference materials shall be homogenous and contain appropriate compositions of each element to be controlled or drift corrected, or both.

9. Preparation of Specimens and Reference Materials

9.1 The specimens and reference materials must be prepared in the same manner. A specimen cut from a large sample section must be of sufficient size and thickness for preparation and to properly fit the spectrometer stand. A 10-mm to 38-mm thick specimen is normally most practical.

9.2 Ensure the specimens are free from voids and pits in the region to be excited (Note 6). Initially grind the surface with a

TABLE 1 Internal Standard and Analytical Lines

Element	Wavelength, nm	Line Classification ^A	Possible Interference ^B
Aluminum	394.40	I	V, Mn, Mo, Ni
	308.22	I	V, Mn
Arsenic	197.20	I	Mo, W
	193.76	I	Mn
Boron	182.64	I	S, Mn, Mo
	182.59	I	W, Mn, Cu
Calcium	396.85	II	Nb
Carbon	193.09	I	Al
Chromium	298.92	II	Mn, V, Ni, Nb, Mo
	267.72	II	Mn, Mo, W
Cobalt	345.35	I	Cr, Mo
	228.62	II	Ni, Cr
Copper	327.40	I	Nb
	213.60	II	Mo, Cr
Iron (IS)	271.44	II	
	273.07	II	Co
Manganese	293.31	II	Cr, Mo, Ni
	255.86	II	Zr
Molybdenum	379.83	II	Mn
	277.54	I	Cu, V, Co, Mn
	386.41	I	V, Cr
Nickel	231.60	II	Co, Ti
	227.02	II	Nb, W
Niobium	319.50	II	Mo, Al, V
Nitrogen	149.26	I	Fe, Ti, Si, Mn, Cu, Ni and nitride forming elements such as Ti
Phosphorus	178.29	I	Mo
Silicon	288.16	I	Mo, Cr, W
	251.61	I	Fe, V
Sulfur	180.73	I	Mn
Tin	189.99	II	Mn, Mo, Al
Titanium	337.28	II	Nb
	324.20	II	Nb
Vanadium	310.23	II	Fe, Mo, Nb, Ni
	311.07	II	Mn, Ti, Fe
Zirconium	343.82	II	W

^A The numerals I or II in the line classification column indicate that the line has been classified in a term array and definitely assigned to the normal atom (I) or to the singly ionized atom (II).

^B Interferences are dependent upon instrument design, spectrum line choices, and excitation conditions, and those listed require confirmation based upon specimens selected especially to demonstrate suspected interferences.

TABLE 2 Other Analytical Lines

Element	Wavelength, nm	Line Classification ^A	Possible Interference ^B
Arsenic	189.04	I	V, Cr
Carbon	165.81	I	
Copper	224.26	II	Ni
	324.75	I	Mn, Nb
Molybdenum	202.03	II	
	281.62	II	Mn
Silicon	212.415	II	Mo, Ni, V, Cu, Nb

^A The numerals I or II in the line classification column indicate that the line has been classified in a term array and definitely assigned to the normal atom (I) or to the singly ionized atom (II).

^B Interferences are dependent upon instrument design, dispersion, spectrum line choices, and excitation conditions, and those listed require confirmation based upon specimens selected especially to demonstrate suspected interferences.

50-grit to 80-grit abrasive belt or disc (wet or dry). Perform the final grind with a dry abrasive belt or disc. A finer abrasive grinding media (for example, 120-grit) may be used for the final grind, but is not essential.

NOTE 6—Specimen porosity is undesirable because it leads to the improper “diffuse-type” rather than the desired “concentrated-type” discharge. The specimen surface should be kept clean because the specimen is the electron emitter, and electron emission is inhibited by oily, dirty surfaces.

9.2.1 Reference materials and specimens must be refinished dry on an abrasive belt or disc before being re-excited on the same area.

10. Preparation of Apparatus

NOTE 7—The instructions given in this test method apply to most spectrometers; however, some settings and adjustments may need to be varied, and additional preparation of the equipment may be required. It is not within the scope of an ASTM test method to prescribe the minute details of the apparatus preparation, which may differ not only for each manufacturer, but also for different equipment from the same manufacturer. For a description of and further details of operation of a particular spectrometer, refer to the manufacturer’s handbook.

10.1 Program the spectrometer to accommodate the internal standard lines and one of the analytical lines for each element listed in Table 1. Multiple lines may be used for a given element (for example, nickel) depending on the mass fraction range and the individual spectrometer software.

NOTE 8—The lines listed in Table 1 have proven satisfactory for the elements and mass fraction ranges described in the scope. Other internal standard and analytical lines, such as those listed in Table 2, may be used provided that it can be shown experimentally that equivalent precision and accuracy are obtained.

10.2 Test the positioning of the spectrometer entrance slit to ensure that peak radiation is entering the spectrometer chamber. This shall be done initially and as often as necessary to maintain proper entrance slit alignment. Follow the manufacturer’s recommended procedures. The laboratory will determine the frequency of positioning the alignment based on instrument performance.

10.3 Exit slit positioning and alignment is normally performed by the manufacturer at spectrometer assembly. Under normal circumstances, further exit slit alignment is not necessary (**Note 9**).

NOTE 9—The manner and frequency of positioning or checking the position of the exit slits will depend on factors such as: the type of spectrometer, the variety of analytical problems encountered, and the frequency of use. Each laboratory should establish a suitable check procedure utilizing qualified service engineers.

11. Excitation and Exposure

11.1 Electrical Parameters:

11.1.1 Excitation parameters are normally established by the spectrometer manufacturer. The following ranges are historical guidelines and newer instruments may vary from these.

Triggered Capacitor Discharge	
Capacitance, μF	10 to 15
Inductance, μH	50 to 70
Resistance, Ω	3 to 5
Potential, V	940 to 1000
Current, A, r-f	0.3 to 0.8
Number of discharges	60

11.1.2 When parameter values are established, maintain them carefully. The variation of the power supply voltage shall not exceed $\pm 5\%$ and preferably should be held within $\pm 2\%$.

11.1.3 *Initiation Circuit*—The initiator circuit parameters shall be adequate to uniformly trigger the capacitor discharge. The following settings are historical guidelines and newer instruments may vary from these:

Capacitance, μF	0.0025
Inductance, μH	residual
Resistance, Ω	2.5
Peak voltage, V	18 000

11.1.4 *Other Electrical Parameters*—Excitation units, on which the precise parameters given in 11.1.1 and 11.1.3 are not available, may be used provided that it can be shown experimentally that equivalent precision and accuracy are obtained.

11.2 *Excitation Conditions*—The following ranges are normally adequate:

Argon flush period, s	5 to 15
Preburn period, s	5 to 20
Exposure period, s	3 to 30

Argon flow	ft^3/h	L/min
Flush	5 to 45	2.5 to 25
Preburn	5 to 45	2.5 to 25
Exposure	5 to 30	2.5 to 15

11.2.1 Select preburn and exposure periods after a study of volatilization rates during specimen excitations. Once established, maintain the parameters consistently.

11.2.2 A high-purity argon atmosphere is required at the analytical gap. Molecular gas impurities, nitrogen, oxygen, hydrocarbons, or water vapor, either in the gas system or from improperly prepared specimens should be minimized.

11.3 *Electrode System*—The specimen, electrically negative, serves as one electrode. The opposite electrode is a thoriated tungsten or silver rod, the tip of which has been machined to a 90° or 120° angled cone. Use either a 3 mm, 4 mm, or 5 mm (± 0.1 mm) analytical gap. Condition a fresh counter electrode with two to six excitations using the operating conditions described in 11.1 and 11.2.

11.4 *Photomultiplier Potentials*—The sensitivity of the photomultiplier is normally established and set by the spectrometer manufacturer based on the particular wavelengths selected.

11.4.1 The range of anode to cathode potentials for a given tube should be specified, that is 650 V dc to 1000 V dc. If within the potential range the tube is either too sensitive or too insensitive for the element concentration range, select another photomultiplier. The potentials on the capacitors may be read directly, or a number of different readout systems may be employed, which yield linear or logarithmic functions of the potentials and which may be displayed as relative numbers or as numbers calibrated directly in terms of mass fraction percent.

12. Calibration, Standardization, and Verification

12.1 *Calibration*—Using the conditions given in 11.1 – 11.3, excite calibrants and potential drift correction samples in a random sequence, bracketing these with excitations of any materials intended for use as verifiers. (A verifier may be used as a calibrant even though it is burned only as a verifier.) There shall be at least three calibrants for each element, spanning the required concentration range. Excite each calibrant, drift correction sample, and verifier two to four times and use the average value. If the spectrometer system and software permits, repeat with different random sequences at least two times. Using the averages of the data for each point, determine analytical curves as directed in the spectrometer manufacturer's software or Practice E305.

12.2 *Standardization*—Following the manufacturer's recommendations, standardize on an initial setup or anytime that it is known or suspected that readings have shifted. Make the necessary corrections either by adjusting the controls on the readout or by applying arithmetic corrections. Standardization will be done anytime verification indicates that readings have gone out of statistical control.

12.3 *Verification*—Verify that the instrument's standardization is valid immediately after each standardization and as required in accordance with 12.3.2.

12.3.1 Analyze verifiers in accordance with Section 13. If results do not fall within the control limits established in 12.4, run another standardization or investigate why the instrument may be malfunctioning.

12.3.2 Each laboratory shall determine the frequency of verification necessary based on statistical analysis. Typically every 4 h to 8 h is practical and adequate. If the results are not within the control limits established in 12.4, perform a standardization and repeat verification. Repeat standardization as necessary so verifications are within control limits or investigate further for instrument problems.

12.4 *Quality Control*—Establish control limits in accordance with ASTM MNL 7, Practice E1329, or other equivalent quality control procedure.

13. Excitation and Radiation Measurements

13.1 Place the prepared surface of the specimen on the excitation stand so that excitation will impinge on a location approximately 6 mm ($\frac{1}{4}$ in.) from the edge of the specimen.

NOTE 10—With certain spectrometers, a properly excited specimen usually exhibits a dark ring around the pitted sparked area. With that equipment, a smooth, white, texture burn without the characteristic dark ring indicates an improperly excited specimen. However, if boron nitride disks are used to mechanically restrict the excited area of the sample, a properly excited specimen may not exhibit a dark ring.

13.2 Excite specimens in duplicate and report the average of the duplicate results.

14. Calculation

14.1 Using the average results obtained in 13.2, calculate the mass fraction % of the elements from the analytical curves developed in 12.1.

15. Precision and Bias

15.1 *Precision*—Up to eight laboratories cooperated in performing this test method and obtained the statistical information summarized in Table 3. Additional data for within-laboratory variability of results, obtained by analyzing three specimens of one material in seven laboratories in accordance with source conditions specified in this method, are given in Table 4. Other specimens may exhibit greater or less variability using the same instrument and excitation conditions.

TABLE 3 Statistical Information (Test Method E415 Extension Study)

Element	Average Mass Fraction %	Number of Laboratories	Repeatability, R_1^A	Relative Repeatability, %	Reproducibility, R_2^A	Relative Reproducibility, %
Aluminum	0.0669	7	0.004	5.98	0.025	34.7
	0.0625	5	0.003	4.80	0.023	36.8
	0.0212	7	0.005	23.6	0.011	51.9
Antimony	0.0038	2	0.0007	18.4	0.001	26.3
Arsenic	0.0415	6	0.005	12.0	0.0272	65.6
	0.0144	6	0.007	48.6	0.0247	172.
Boron	0.0063	7	0.0007	11.1	0.0011	17.5
	0.0038	7	0.0007	18.4	0.0042	110.
	0.0006	7	0.0003	50.0	0.0009	150.
Carbon	1.054	7	0.053	5.03	0.108	10.2
	0.507	7	0.025	4.93	0.061	12.0
	0.033	7	0.025	75.8	0.042	127.
Chromium	1.574	7	0.043	3.38	0.176	13.8
	1.307	6	0.123	9.41	0.124	9.49
	2.128	7	0.057	2.68	0.232	10.9
	0.118	7	0.003	2.54	0.011	9.32
	0.093	7	0.003	3.23	0.008	8.60
Cobalt	0.157	4	0.008	5.10	0.057	36.3
	0.114	7	0.011	9.65	0.023	20.2
	0.0086	8	0.0007	8.14	0.004	46.5
Copper	0.435	7	0.025	5.75	0.039	8.97
	0.150	7	0.009	6.00	0.026	17.3
	0.054	7	0.008	14.8	0.022	40.7
Manganese	1.893	7	0.052	2.75	0.181	9.56
	1.494	7	0.052	3.48	0.141	9.44
	0.559	7	0.023	4.11	0.074	13.2
	0.316	7	0.013	4.11	0.051	16.1
Molybdenum	0.561	7	0.012	2.14	0.168	29.9
	0.325	7	0.008	2.46	0.037	11.4
	0.147	7	0.005	3.40	0.016	10.9
Nickel	4.796	6	0.275	5.73	0.691	14.1
	2.208	7	0.112	5.07	0.164	7.43
	0.180	6	0.012	6.67	0.022	12.2
	0.108	7	0.006	5.56	0.010	9.26
	0.0578	7	0.003	5.19	0.015	26.0
Niobium	0.076	7	0.007	9.21	0.010	13.2
	0.0084	5	0.003	35.7	0.018	214.
	0.0078	5	0.003	38.5	0.014	179.
Phosphorus	0.0775	7	0.005	6.45	0.017	21.9
	0.0379	7	0.003	7.92	0.012	31.7
	0.0124	7	0.003	24.2	0.009	72.6
Silicon	1.063	7	0.031	2.92	0.107	10.1
	0.391	7	0.015	3.84	0.099	25.3
	0.176	7	0.006	3.41	0.035	19.9

TABLE 3 *Continued*

Element	Average Mass Fraction %	Number of Laboratories	Repeatability, R_1^A	Relative Repeatability, %	Reproducibility, R_2^A	Relative Reproducibility, %
Sulfur	0.0505	7	0.006	11.9	0.015	29.7
	0.0209	7	0.005	28.9	0.007	33.5
	0.0146	7	0.002	13.7	0.005	41.1
Tin	0.040	7	0.002	5.00	0.024	60.0
	0.024	7	0.002	8.33	0.011	45.8
	0.0056	7	0.001	17.9	0.007	125.
Titanium	0.190	7	0.024	12.6	0.045	23.7
	0.029	7	0.004	13.8	0.017	58.6
	0.0019	7	0.0007	36.8	0.002	105.
Vanadium	0.279	7	0.007	2.51	0.041	14.7
	0.091	7	0.002	2.20	0.015	16.5
	0.0026	7	0.0002	7.69	0.002	76.9
Zirconium	0.0439	5	0.006	13.7	0.009	20.5
	0.0075	5	0.002	26.7	0.012	160.
	0.0025	5	0.001	40.0	0.008	320.

^A R_1 is equivalent to r , Practice E1601; R_2 is equivalent to R , Practice E1601.

TABLE 4 Variability of Results Within Individual Laboratories (NBS 1262)

Element NIST Value	Average Mass Fraction %	Laboratory	Standard Deviation, Mass Fraction % ^A	Relative Standard Deviation, RSD % ^B	Element NIST Value	Average Mass Fraction %	Laboratory	Standard Deviation, Mass Fraction % ^A	Relative Standard Deviation, RSD % ^B
Aluminum 0.095	0.087	1	0.0032	3.70	Molybdenum 0.068	0.068	1	0.0012	1.46
	0.0936	2	0.0047	5.03		0.0681	2	0.0040	5.91
	0.0823	3	0.0083	10.10		0.0663	3	0.00173	2.60
	0.0992	4	0.0030	3.01		0.069	4	0.00064	0.92
	0.0999	5	0.0019	1.90		0.068	5	0.0011	1.60
	0.095	6	0.0015	1.58		0.069	6	0.00068	0.98
	0.0899	7	0.0012	1.36		0.0645	7	0.0005	0.73
Antimony 0.012	0.0125	1	0.0018	14.40	Nickel 0.59	...	1	no value	no value
	no value	2	no value	no value		0.597	2	0.0078	1.31
	no value	3	no value	no value		0.560	3	0.0069	1.22
	no value	4	no value	no value		0.589	4	0.0022	0.36
	no value	5	no value	no value		0.606	5	0.0097	1.60
	0.0110	6	0.00031	2.85		0.589	6	0.00443	0.75
	no value	7	no value	no value		0.556	7	0.0027	0.49
Arsenic 0.076	0.060	1	0.0024	4.00	Niobium 0.29	0.290	1	0.0120	4.10
	no value	2	no value	no value		0.292	2	0.0108	3.69
	0.1085	3	0.0045	4.16		0.321	3	0.0098	3.06
	no value	4	no value	no value		0.292	4	0.0037	1.26
	0.0718	5	0.0029	4.00		0.289	5	0.0137	4.70
	0.0871	6	0.00243	2.79		0.283	6	0.0059	2.08
	0.0784	7	0.0021	2.64		0.2636	7	0.0042	1.58
Boron 0.0025	0.0026	1	0.00040	15.40	Phosphorus 0.042	0.0414	1	0.0022	5.30
	0.00174	2	0.00043	24.68		0.0355	2	0.00144	4.04
	0.0030	3	0.0003	10.13		0.0414	3	0.0012	2.85
	0.00257	4	0.00009	3.50		0.0394	4	0.00039	1.00
	0.00303	5	0.00014	4.60		0.040	5	0.0014	3.50
	0.00242	6	0.00007	2.89		0.0369	6	0.00063	1.72
	0.0028	7	0.0001	2.23		0.0342	7	0.0004	1.30
Carbon 0.16	0.160	1	0.0080	5.00	Silicon 0.39	0.403	1	0.0046	1.14
	0.164	2	0.0094	5.76		0.392	2	0.0058	1.49
	0.158	3	0.0046	2.92		0.393	3	0.0126	3.21
	0.162	4	0.0022	1.37		0.398	4	0.0030	0.75
	0.159	5	0.007	4.40		0.389	5	0.0059	1.50
	0.159	6	0.0037	2.29		0.437	6	0.0032	0.73
	0.162	7	0.0038	2.24					
Chromium 0.30	0.296	1	0.0048	1.62	Sulfur 0.038	0.0376	1	0.0020	5.30
	0.300	2	0.0038	1.28		0.0404	2	0.00239	5.94
	0.309	3	0.0039	1.26		0.0363	3	0.00118	2.85
	0.302	4	0.0015	0.49		0.0387	4	0.00103	2.65
	0.300	5	0.0032	1.10		0.0392	5	0.0014	3.50

TABLE 4 *Continued*

Element NIST Value	Average Mass Fraction %	Laboratory	Standard Deviation, Mass Fraction % ^A	Relative Standard Deviation, RSD % ^B	Element NIST Value	Average Mass Fraction %	Laboratory	Standard Deviation, Mass Fraction % ^A	Relative Standard Deviation, RSD % ^B
	0.304	6	0.00220	0.72		0.0376	6	0.00132	3.51
	0.298	7	0.0020	0.68		0.0375	7	0.0014	3.78
Cobalt 0.30	0.299	1	0.0054	1.80	Tin 0.016	0.0164	1	0.00067	3.75
	0.302	2	0.0044	1.45		0.0157	2	0.00048	3.08
	0.252	3	0.0137	5.45		0.0207	3	0.00046	2.21
	0.304	4	0.0020	0.66		0.0178	4	0.00072	4.04
	no value	5	no value	no value		0.0158	5	0.0026	2.90
	0.299	6	0.00597	2.00		0.016	6	0.00044	2.77
	0.3038	7	0.0029	0.97		0.0175	7	0.0004	2.27
Copper 0.50	0.499	1	0.0116	2.32	Titanium 0.084	0.079	1	0.0043	5.44
	0.502	2	0.0098	1.95		0.089	2	0.0025	2.81
	0.494	3	0.0212	4.28		0.0899	3	0.000324	3.60
	0.505	4	0.00346	0.69		0.091	4	0.0011	1.17
	0.496	5	0.012	2.40		0.0882	5	0.0005	1.30
	0.499	6	0.00852	1.71		0.085	6	0.00135	1.59
	0.534	7	0.0099	1.85		0.1073	7	0.0017	1.55
Manganese 1.04	1.056	1	0.0092	0.87	Vanadium 0.041	0.040	1	0.00037	0.92
	1.00	2	0.0081	0.81		0.0402	2	0.00054	1.34
	1.10	3	0.0143	1.29		0.0410	3	0.0010	2.43
	1.050	4	0.0072	0.69		0.0413	4	0.00022	0.52
	1.038	5	0.015	1.50		0.0387	5	0.0005	1.30
	1.016	6	0.0117	1.15		0.039	6	0.00036	0.92
	1.038	7	0.0087	0.84		0.0458	7	0.0004	0.78
Zirconium 0.19	0.192	1	0.0089	4.70	Zirconium 0.19	0.191	5	0.0081	4.20
	no value	2	no value	no value		0.173	6	0.00495	2.863
	0.305	3	0.0177	5.81		0.1941	7	0.0070	3.611
	0.187	4	0.0048	2.58					

^A Standard Deviation (*s*) was calculated as follows:

$$s = \sqrt{\frac{\sum d^2}{N-1}}$$

where:

d = difference of determination from mean, and
N = number of determinations.

^B Relative Standard Deviation (RSD) was calculated as follows:

$$RSD = \frac{s}{\bar{x}} (100)$$

where:

s = standard deviation, and
 $\bar{x}$ = average mass fraction %.

15.1.1 Precision for Calcium and Nitrogen—Up to eight laboratories cooperated in performing this test method and obtained the precision information summarized in **Table 5**.⁵ An approximate value for the expected reproducibility index, *R*, in the range of 0 % to 0.0030 % calcium can be calculated from the following equation in which Ca % is the expected calcium level:

$$R = \sqrt{[0.00048^2 + (Ca \% \times 0.30)^2]} \quad (1)$$

15.1.2 For nitrogen, the reproducibility index, *R*, has the approximate value of 0.0020 throughout the range of 0 % to 0.015 % nitrogen.

⁵ Supporting data have been filed at ASTM International Headquarters and may be obtained by requesting Research Report: RR:E01-1022.

NOTE 11—The interlaboratory test data summarized in **Tables 5 and 6** have been evaluated in accordance with Practice **E1601**.

15.2 Bias—At least three specimens that previously had been analyzed by chemical techniques in more than one laboratory were analyzed following the conditions of this test method. The data are given in **Table 7 (Note 11)**.

15.2.1 Bias for Calcium and Nitrogen—The bias of this test method at certain mass fraction levels may be judged by comparing the accepted reference values with the arithmetic average obtained by interlaboratory testing (see **Table 6**).

16. Keywords

16.1 carbon steel; low-alloy steel; spark atomic emission; spectrometric analysis; spectrometry

TABLE 5 Statistical Information for Calcium and Nitrogen

Test Material	Number of Laboratories	Found, Mass Fraction %	Minimum SD (S_{Mf} , Practice E1601)	Reproducibility SD (S_R , Practice E1601)	Reproducibility Index (R , Practice E1601)	R_{rel} %
Calcium						
C	6	0.00020	0.000021	0.000175	0.00049	250
G	7	0.00036	0.000025	0.000181	0.00051	139
H	8	0.00106	0.000075	0.000210	0.00059	55.7
F	8	0.00118	0.000134	0.000249	0.00070	59.0
D	8	0.00149	0.000135	0.000231	0.00065	43.3
J	8	0.00186	0.000129	0.000298	0.00083	45.0
A	8	0.00201	0.000119	0.000218	0.00061	30.3
I	8	0.00207	0.000064	0.000181	0.00051	24.4
B	8	0.00267	0.000182	0.000328	0.00092	34.4
E	8	0.00288	0.000258	0.000436	0.00122	42.5
Nitrogen						
C	8	0.00125	0.000143	0.000781	0.00218	175
E	8	0.00400	0.000169	0.000787	0.00220	55.7
F	8	0.00478	0.000175	0.000779	0.00218	45.6
H	8	0.00509	0.000157	0.000684	0.00192	37.6
G	8	0.00751	0.000247	0.000715	0.00200	26.7
D	8	0.00817	0.000218	0.000650	0.00182	22.2
B	8	0.00977	0.000264	0.000587	0.00164	16.8
A	8	0.01289	0.000239	0.000603	0.00169	13.1
I	8	0.01364	0.000264	0.000813	0.00228	16.7

TABLE 6 Bias Information for Calcium and Nitrogen

Test Material	Assumed True Value, Mass Fraction %	Average Spectrometer Value, Mass Fraction %	Difference, Mass Fraction %	Material Identification, Uncertainty or (SD)		Low Alloy Steel Description
Calcium						
C	0.00027	0.00020	−0.00007	BS CA4A	0.00004	chill-cast
G	0.0004	0.00036	−0.00004	BS CCS 1	(0.00005)	wrought
H	0.0011	0.00106	−0.00004	ST 06	(0.00013)	wrought
F	0.0014	0.00118	−0.00022	BS 58G	(0.00019)	wrought
D	0.0016	0.00149	−0.00011	BS 54D	(0.00015)	wrought
J	0.0021	0.00186	−0.00024	ST 08	(0.00014)	wrought
A	0.0018	0.00201	0.00021	BS CA1A	(0.0003)	chill-cast
I	0.0022	0.00207	−0.00003	ST 07	(0.0002)	wrought
B	0.0029	0.00267	−0.00023	BS CA2A	(0.0003)	chill-cast
E	0.0033	0.00288	−0.00042	BS CSN 2D	(0.0003)	wrought
Nitrogen						
C	0.0011	0.00125	0.00015	BS 54D	(0.0003)	wrought
E	0.0036	0.00400	0.00040	BS XAAS	(0.00025)	wrought
F	0.0044	0.00478	0.00038	BS XCCS	(0.00025)	wrought
H	0.0056	0.00509	−0.00051	BS XCCV	(0.00024)	wrought
G	0.0074	0.00751	−0.00009	BS XCCT	(0.0002)	wrought
D	0.0087	0.00817	−0.00053	BS 56G	(0.0004)	wrought
B	0.0106	0.00977	−0.00083	BS CA4A	(0.0007)	chill-cast
A	0.0135	0.01289	−0.00061	BS CA1A	(0.00075)	chill-cast
I	0.0136	0.01364	0.00004	BS 46A	(0.00038)	wrought

TABLE 7 Bias Data

Element	Assumed True Value, Mass Fraction %	Average Spectrometer Value, Mass Fraction %	Number of Laboratories	Deviation from Assumed True Value, Mass Fraction%	Element	Assumed True Value, Mass Fraction %	Average Spectrometer Value, Mass Fraction%	Number of Laboratories	Deviation from Assumed True Value, Mass Fraction %
Aluminum	0.04 0.058	0.038 0.062	4 4	0.00 +0.004		0.35 0.56	0.34 0.54	5 3	-0.01 -0.02
Boron	0.007	0.006	7	-0.001	Niobium	0.023 0.10	0.024 0.11	2 2	+0.001 +0.01
Carbon	0.073 0.22 0.50 0.67	0.072 0.21 0.51 0.66	5 5 7 5	-0.001 -0.01 +0.01 -0.01	Phosphorus	0.005 0.009 0.036 0.046 0.089	0.005 0.009 0.038 0.042 0.078	5 5 7 5 7	0.000 0.000 +0.002 -0.004 -0.011
Chromium	0.05 0.08 0.37 0.85 1.51	0.05 0.09 0.35 0.85 1.57	5 7 5 3 7	0.00 +0.01 -0.02 0.00 +0.06	Silicon	0.024 0.18 0.19 0.35 0.40	0.029 0.18 0.18 0.36 0.39	3 7 5 5 7	+0.005 0.00 -0.01 +0.01 -0.01
Cobalt	0.12 0.17	0.11 0.16	7 4	-0.01 -0.01	Sulfur	0.008 0.032 0.034 0.053	0.006 0.028 0.038 0.051	4 5 3 7	-0.002 -0.004 +0.004 -0.002
Copper	0.016 0.056 0.070 0.101	0.017 0.054 0.065 0.098	3 7 3 3	+0.001 -0.002 -0.005 -0.003	Tin	0.004 0.008 0.024 0.028 0.044	0.005 0.008 0.025 0.024 0.040	5 5 5 7 7	+0.001 0.000 +0.001 -0.004 -0.004
Manganese	0.44 0.57 0.98 1.43	0.43 0.58 0.94 1.49	5 5 5 7	-0.01 +0.01 -0.04 +0.06	Titanium	0.002 0.027	0.002 0.029	7 7	0.000 +0.002
Molybdenum	0.008 0.10 0.14 0.33 0.34	0.012 0.10 0.15 0.33 0.36	4 4 7 7 3	+0.004 0.00 +0.01 0.00 +0.02	Vanadium	0.002 0.012 0.135 0.27	0.002 0.012 0.138 0.28	2 2 2 7	0.000 0.000 +0.003 +0.01
Nickel	0.034 0.10	0.038 0.11	5 7	+0.004 +0.01					

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